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IRFM9240

POWER MOSFET THRU-HOLE (TO-254AA)

Product Summary

	Part Number	RDS(on)	ID
I	IRFM9240	0.51Ω	-11A

200V, P-CHANNEL

Features:

- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed
- Electrically Isolated
- Dynamic dv/dt Rating
- Light-weight

Absolute Maximum Ratings

	Parameter		Units	
$I_D @ V_{GS} = -10V, T_C = 25^{\circ}C$	Continuous Drain Current	-11		
$I_D @ V_{GS} = -10V, T_C = 100^{\circ}C$	Continuous Drain Current	-7.0	Α	
IDM	Pulsed Drain Current ①	-44		
P _D @ T _C = 25°C	Max. Power Dissipation	125	W	
	Linear Derating Factor	1.0	W/°C	
VGS	Gate-to-Source Voltage	±20	V	
EAS	Single Pulse Avalanche Energy 2	500	mJ	
IAR	Avalanche Current ①	-11	Α	
EAR	Repetitive Avalanche Energy ①	12.5	mJ	
dv/dt	Peak Diode Recovery dv/dt 3	-5.0	V/ns	
TJ	Operating Junction	-55 to 150		
TSTG	Storage Temperature Range		°C	
	Lead Temperature	300 (0.063 in.(1.6mm) from case for 10s)		
	Weight	9.3 (typical)	g	

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Quality Semi-Conductors

IRFM9240

Electrical Characteristics @ Tj = 25°C (Unless Otherwise Specified)

	Parameter	Min	Тур	Max	Units	Test Conditions
BVDSS	Drain-to-Source Breakdown Voltage	-200	_	_	V	$V_{GS} = 0V, I_{D} = -1.0 \text{mA}$
ΔBVDSS/ΔTJ	Temperature Coefficient of Breakdown Voltage	_	-0.2	_	V/.°C	Reference to 25°C, ID = -1.0mA
RDS(on)	Static Drain-to-Source On-State	_	-	0.51	Ω	$V_{GS} = -10V, I_{D} = -7.0A$
1.00(011)	Resistance	_	_	0.52	\$2	VGS = -10V, ID = -11A @
VGS(th)	Gate Threshold Voltage	-2.0	_	-4.0	V	$V_{DS} = V_{GS}$, $I_{D} = -250\mu A$
9fs	Forward Transconductance	4.0	_	_	S (75)	$V_{DS} > -15V$, $I_{DS} = -7.0A$ (4)
IDSS	Zero Gate Voltage Drain Current	_	_	-25		V _{DS} = -160V, V _{GS} = 0V
.000	, and the second	_	_	-250	μА	$V_{DS} = -160V$
						$V_{GS} = 0V, T_J = 125^{\circ}C$
IGSS	Gate-to-Source Leakage Forward	_	_	-100	nA	VGS = -20V
IGSS	Gate-to-Source Leakage Reverse	_	_	100	IIA	VGS =20V
Qg	Total Gate Charge	_	_	60		VGS = -10V, ID= -11A
Qgs	Gate-to-Source Charge	_	_	15	nC	V _{DS} = -100V
Qgd	Gate-to-Drain ('Miller') Charge	_	_	38		
td(on)	Turn-On Delay Time	_	_	35		$V_{DD} = -100V, I_{D} = -11A,$
tr	Rise Time	_	_	85	ns	$R_G = 9.1\Omega$, $V_{GS} = -10V$
td(off)	Turn-Off Delay Time	_	_	85] 115	
tf	Fall Time	_	-	65		
LS + LD	Total Inductance	_	6.8	_	nH	Measured from drain lead (6mm/ 0.25in. from package) to source lead (6mm/0.25in. from package)
Ciss	Input Capacitance	_	1200	-		VGS = 0V, VDS = -25V
Coss	Output Capacitance	_	570	_	pF	f = 1.0MHz
Crss	Reverse Transfer Capacitance	_	81	_		

Source-Drain Diode Ratings and Characteristics

	Parameter	Min	Тур	Max	Units	Test Conditions
Is	Continuous Source Current (Body Diod	e) —	_	-11	A	
ISM	Pulse Source Current (Body Diode) ①	_	_	-44		
VSD	Diode Forward Voltage		_	-4.6	V	$T_j = 25$ °C, $I_S = -11A$, $V_{GS} = 0V$ ④
trr	Reverse Recovery Time	_	_	440	nS	$T_j = 25$ °C, $I_F = -11A$, $di/dt \le -100A/\mu s$
QRR	Reverse Recovery Charge	_	1-	7.2	μc	V _{DD} ≤ -50V ④
ton	Forward Turn-On Time Intrinsic tur	n-on time i	s neglig	jible. Tu	rn-on spe	eed is substantially controlled by LS + LD

Thermal Resistance

	Parameter	Min	Тур	Max	Units	Test Conditions
RthJC	Junction-to-Case	_	-	1.0		
RthCS	Case-to-sink	_	0.21	_	°C/W Typical socket m	
RthJA	Junction-to-Ambient	_	_	48		Typical socket mount